

<b>Notice of References Cited</b>	Application/Control No. 10/643,074	Applicant(s)/Patent Under Reexamination ALCORN ET AL.	
	Examiner Songwei Qian	Art Unit 2191	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,909,589 A	06-1999	Parker et al.	712/32
*	B	US-6,006,279 A	12-1999	Hayes, Persnaz Neli	719/328
*	C	US-6,289,512 B1	09-2001	Edwards et al.	717/178
*	D	US-2002/0184610 A1	12-2002	Chong et al.	717/109
*	E	US-2002/0184401 A1	12-2002	Kadel et al.	709/315
*	F	US-6,557,100 B1	04-2003	Knutson, James Irwin	713/100
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Venkat Govi, Hernan Eguiluz, You Jung Kim, and Adrain Sia, "System test plan", June 8, 2002, retrieved from <a href="http://dogbert.mse.cs.cmu.edu/mse2002/projects/pamd1/Working%20Document/PUMASystemTestPlan_v.1.0.doc">http://dogbert.mse.cs.cmu.edu/mse2002/projects/pamd1/Working%20Document/PUMASystemTestPlan_v.1.0.doc</a> on September 4, 2007
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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